Search Notes



Application/Control No	. Applicant(s)/Patent under Reexamination	-
09/614,660	KIROVSKI ET AL.	
Examiner	Art Unit	
Christopher A. Revak	2131	

	SEARCHED		
Class	Subclass	Date	Examiner
NOWE	かかんと	GIHIOS	ar
. ,			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
380	200-203	4/21/2005	CR
380	205,210	4/21/2005	CR
380	236-238	4/21/2005	CR
	14,243,246, ,253	4/21/2005	CR

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
BRS Text Search USPAT, DERWENT, JPO, EPO, IBM TDB, US PGPUB, USOCR	9/14/2005	CR
DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE	9/14/2005	CR
101 Help Panel	9/14/2005	CR

Search Notes (continued)



Application/Control No.	Applicant(s)/Patent under Reexamination
09/614,660	KIROVSKI ET AL.
Examiner	Art Unit
Christopher A. Revak	2131

			•
	SEAR	CHED	
Class	Subclass	Date	Examiner
-		-	
:			
			1

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
382	232,248	4/21/2005	CR
382	250,276	4/21/2005	CR
382	280	4/21/2005	CR
713	/176	4/21/2005	CR

SEARCH (INCLUDING SEAR	NOTES ICH STRATEGY	()
	DATE	EXMR
·		
		-